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INFORMATION DISCLOSURE STATEMENT BY APPLICANT					ATTY. DOCKET NO. 044117-0143		SERIAL NO. 10/539,771				
					APPLICANT Eric PINET, et al.						
(Substitute for form 1449/PTO)					FILING DATE January 10, 20		GROUP 1797				
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XAMINER'S INITIALS	NO.	Document Number Number-Kind Code2 (# movn)		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document		Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear				
		US	2,106,744	Feb. 1, 1938	Hood, et al.		T				
		US	2,221,709	Nov. 12, 1940	Hood et al.						
		US	2,286,275	June 16, 1942 Hood, et al.							
		US	4,146,887	Mar 27, 1979	Hagnante						
		US	4,154,586	May 15, 1979	Jones, et al.						
		US	4,155,358	May 22, 1979	McAllister, et a	ıl.					
		US	4,326,514	Apr 4, 1982	Elan						
		US	4,530,706	July 23, 1985	Jones						
		US	4,597,942	July 1, 1986	Meathrel						
		US	4,631,952	Dec 30, 1986	Donaghey						
		US	4,684,380	Aug 4, 1987	Leichnitz						
		US	4,699,511	Oct 13, 1987	Seaver						
		US	4,732,480	Mar 22, 1988	Fortunato, et a						
		US	4,834,496	May 30, 1989	Blyler, Jr., et a						
	_	US	4,846,548 4,847,594	July 11, 1989 July 18, 1999	Klainer Stetter						
		US	4,940,328	July 10, 1990	Hartman						
		US	4,940,328	Mar 5, 1990	Ryan, et al.						
	-	US	RE35355	Oct 22, 1996	Ryan, et al.		-				
		US	5.015.843	May 14, 1991	Seitz, et al.		-				
		US	5,206,118	Apr 27 1993	Sidney, et al.						
	-	US	5,238,729	Aug 24 1993	Debe		<u> </u>				
		us	5.250.095	Oct 5, 1993	Sigel, Jr., et al		 				
		us	5,308,771	May 3, 1994	Zhou, et al.		 				
		L - L		FOREIGN PAT	ENT DOCUMENTS						
INITIALS CITE Country Co		gn Patent Document y Codes-Number 4-Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document Where Release Figures App		levant	Trans Yes	lation No			
			OTHER A	RT (Including Author	, Title, Date, Pertinent Pages, E	tc.)					
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			Į	J.S. PATENT	T DOCUMENTS					
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code2 (Fibrown)		Publication Date MM-DD-YYYY			Pages, Columns, Lines, Wher Relevant Passages or Releva Figures Appear			
		us I	5,338,415		Aug 16, 1994		+	Sailor, et al. Robillard		
		US 5,436,167			Jul 25, 1995	-	_			
	t —	US 5,453,624			Sept 26, 1995			Sallor, et al.		
		US	5,512,882		Apr 30, 1996			Stetter, et al.		
		US	5,525,800		Jun 11, 1996			Sanghera, et al.		
		US	5,659,296		Aug 19, 1997			Debe, et al.		
		US	5,783,836		Jul 21, 1998			Liu, et al.		
		US	5,828,798		Oct 27, 1998				Hopenfeld	
		US	6,007,904		Dec 28, 1999			Schwotzer, et al.		
		US	6,031,454		Feb 29, 2000				ejoy et al. ger, et al.	
		US	6,130,748		Oct 10, 2000					
		US	6,248,539		Jun 19, 2001			Ghadiri, et al		
		US	6,278,106		Aug 21, 2001			Muto, et al. Bernard, et al.		
		US	6,375,725		Apr 23, 2002					
		US 6,432,721 Aug 13, 2002			Zook, et al.					
		US	6,610,977		Aug 26 2003		Me		erle	
					ENT DOCUMENTS					
XAMINER'S INITIALS			ign Patent Document by Codes -Number 4 -Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Line Where Relevant Figures Appear		Yes	anslation No	
			EP 0536656	May 3, 2000	G. Schwotzer, et al.					
			WO 0222237	Mar 21, 2002	Curado, et al.					
			OTHER A	RT (Including Author	, Title, Date, Pertinent Pages, El	tc.)				
EXAMMER'S INITIALS INCLUDE name of the author (in CAPITAL LETTERS), title of the article (when appropriate), to journal, serial, symposium, catalog, etc.), date, page(s), votume-issue number(s), publisher, unblished.									е,	
		GELB, L.D. et al, "Phase Separation in Confined Systems", Rep. Prog. Phys. 62, 1999, pp. 1573-1660								
		GROSS, E. et al 'Highly Sensitive Recognition Element Based on Birefringent Porous Silicon Layers', J. Appl. Phys. 90 No.								
		GA	O, J. et al., 'Vapor Sens		7, 2001, pp. 3529-3532 Interferometry From Oxidized M	1icroporous	Silicon Films*	Langmuir 18	i, .	
		GAO.	J. et al. "Porous-Silicon"	Vanour Sensor Base	2002, pp. 2229-2233 d on Laser Interferometry* Appl.	Phys. Lett.	/ol. 77 n6. 20	00. op. 901-	903	
		1	WINER			DATE CONS		pp01-		
		EXA	/Samuel	Siefke/			08/2010			

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		U	S. PATENT	DOCUMENTS						
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		US	EODEIGN DAT	ENT DOCUMENTS						
EXAMINER'S		Foreign Patent Document	Publication Date	ENT DOCUMENTS Name of Patentee or	Page Cal	mne Lines	Tron	slation		
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FXAMINER'S), title of the article (when approx		the item /hor	nk manazina			
INITIALS										
	ļ			154-157 porous silicon films caused by v						
			•	1996, pp. 3001-3003						
	-	ZANGOCIE, S. et al., "Vapor sensitivity of thin porous silicon layers', Sensors and Actuators B 43, 1997, pp. 188- ZANGOCIE, S. et al., "Reversible and irreversible control of optical properties of porous silicon superfiattices by thin Object of the Control of								
			OXIGETION, VEDOUT adsorption, and liquid penetration (J. Vetc. Sq. (ecrinol. A 19(0), 1996, pp. 2911-2912). IORI, T., "Structural anisotropy and birefringence in microporous glasses", j. Am. Ceram. Soc. 61 No. 9-10, 197 434-438.							
		RYOO, R. et al., "Optically transparent, single-crystal-like oriented mesoporous silica films and plates", J. Phys. Chem. 1997, pp. 10610-10813.								
	KO, C.H., et al., "Mesocrystal engineering using non-bonded interaction to obtain optically transparent mesopcrous silica fil and plates with uniform orientation", Micro. Meso. Mat. 21, 1998, pp. 235-243.									
TAKAMORI, T. et al. "Anomalous birefringence in oxide glasses" in "treatise on materials science and technology", Gl vol. 12, 1997, pp. 123-155, Tomozawa M. & Doremus R.H. Eds., Academic Press N.Y.										
ANTROPOVA TV, et al. "Porous glass: inhomogeneiles and light transmission", Opt. Appl. Vol. XXX No. 4, 200 ALTSHULER, G.B., et al., "Spatial dispersion of anisotropy of high-eilica microporous glassess", Opt. Spektrosk. 228-231. ALTSHULER, G.B., et al., "Porous glass spicies", J. Non-Cyrst. Solids 123, 1990, pp. 268-270										
		BURKAT, T.M., et al., "Structural anisotropy and birefringence in porous glass plates", Fiz. Khim. Stekla 17 No. 5, 1991, pp. 781-790								
		HERMAN, P.H. in Colloid Science, 1949, Vol. II, Reversible Systems", H.R. Kruyt Ed., Elsevier Pub. Chap. XII § 6 "Sorption and swelling", pp. 512-580.								
				of on the pore structure of porous 5, 1993, pp. 206-209.						
		LORKOWSKI, H.J., et al., "Optical Polymers with special birefringent properties", Polymers for Advanced Technologies Vol. 7, 1996, pp. 501-506.								
		EXAMINER /Samuel	Siefke/		DATE CONS 10/0	DERED 8/2010				
				AL MOCO ORG. Describes there	inh nitation if					

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			U	S. PATEN	T DOCUMENTS						
EXAMINER'S INITIALS	NO.	Nur	Document Number mber-Kind Codes (# known)	Publication Date MM-DD-YYYY	Name of Patentee or Appli Document		Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear				
		US									
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					TENT DOCUMENTS						
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	-	-									
					r, Title, Date, Pertinent Pages, E						
EXAMINER'S INITIALS	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magaz CITE NO. No.								`		
		LI, Y.Y., et al., "Polymer replicas of photonic porous silicon for sensing and drug delivery applications", Science Vo. 299, 2003, pp. 2045-2047.									
		BEOM-HOAN O et al., "Vapor Sensor Realized in an Ultracompact Polarization Interferometer Built of a Freestanding Porous-Silicon Form Birefringent Film", IEEE Photonics Technology Letters, IEEE Inc., New York, US, vol. 15, no. 6, June 2003 no. 384-385, WPO01716197									
		LIU R et al., "Novel Porous silicon vapor sensor based on polarization interferometry" Sensors and Actuators B, Elsevier Seguida S.A., Lausanne, CH, vol. 87, no. 1, 15 November 2002, pp.58-82 XP 004391077									
		RONG LIU et al., "Forcus silicon vapor sensor based on polarization interferometry" LEOS 2001. 14th Annual Meeting of the IEEE Lasers & Electro-Optics Society. San Diego, CA. Nov. 11-15, 2001, Annual Meeting of the IEEE Lasers and Electro- Optics Society, New York, YT. IEEE, US, vol. 12, pp 262-621, YP. 9010596702									
		KOCYMAN R P H et al., "Optical fiber immunosensor based on polarimetry" Transducers. San Francisco, June 24-27, 1991, Proceedings of the International Conference on Solid State Sensors Andactuators, New York, IEEE, US, vol. Conf. 6, 24 June 1991, pp. 376-377, Yp010037367									
	HEIDEMAN R G et al., "Polarimetric Optical-Fibre Sensor for Biochemical Measurements" Sensors and Actuators B, Elsevier Sequoia S.A., Lausanne, CH, vol. B12, no.3, 15 April 1993, pages 205-212, XP 000397509								rier		
VELDHUIS G J et al., "An integrated optical Bragg-reflector used as a chemo-optical sensor" Pure and Applied Optics, Bristol, GB, vol. 7, no. 1, 1998, pages L23-L26, XP 002087839											
EXAMINER /Samuel Siefke/					10/0	DATE CONS 08/2010	IDERED				

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